



# Hybrid IGBT, 50 A, 650 V AFGHL50T65SQDC

Using the novel field stop 4<sup>th</sup> generation IGBT technology and the 1.5<sup>th</sup> generation SiC Schottky Diode technology, AFGHL50T65SQDC offers the optimum performance with both low conduction and switching losses for high efficiency operations in various applications, especially totem pole bridgeless PFC and Inverter.

#### **Features**

- AEC-Q101 Qualified
- Maximum Junction Temperature :  $T_J = 175$ °C
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(Sat)} = 1.6 \text{ V (Typ.)} @I_C = 50 \text{ A}$
- Fast Switching
- Tighten Parameter Distribution
- No Reverse Recovery/No Forward Recovery

#### **Typical Applications**

- Automotive
- On & Off Board Chargers
- DC-DC Converters
- PFC
- Industrial Inverter

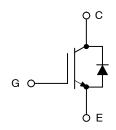
#### **MAXIMUM RATINGS**

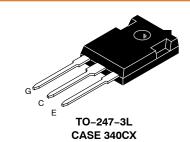
Rating	Symbol	Value	Unit
Collector to Emitter Voltage	$V_{CES}$	650	V
Gate to Emitter Voltage Transient Gate to Emitter Voltage	V <sub>GES</sub>	±20 ±30	V
	I <sub>C</sub>	100 50	Α
Pulsed Collector Current (Note 1)	$I_{LM}$	200	Α
Pulsed Collector Current (Note 2)	I <sub>CM</sub>	200	Α
Diode Forward Current @T <sub>C</sub> = 25°C @T <sub>C</sub> = 100°C	l <sub>F</sub>	40 20	Α
Pulsed Diode Maximum Forward Current	I <sub>FM</sub>	200	Α
Maximum Power Dissipation $@T_C = 25^{\circ}C$ $@T_C = 100^{\circ}C$	P <sub>D</sub>	238 119	W
Operating Junction / Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	±55 to +175	°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

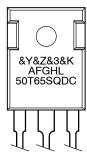
- 1.  $V_{CC}=400$  V,  $V_{GE}=15$  V,  $I_{C}=200$  A,  $R_{G}=26$   $\Omega$ , Inductive Load, 100% Tested.
- 2. Repetitive Rating: pulse width limited by max. Junction temperature.

# 50 A, 650 V V<sub>CESat</sub> = 1.6 V (Typ.)





#### **MARKING DIAGRAM**



&Y = onsemi Logo &Z = Assembly Plant Code &3 = 3-Digit Data Code

&K = 2-Digit Lot Traceability Code AFGHL50T65SQDC = Specific Device Code

#### **ORDERING INFORMATION**

Device	Package	Shipping
AFGHL50T65SQDC	TO-247-3L	30 Units / Rail

### THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.63	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	1.55	°C/W
Thermal resistance junction-to-ambient	$R_{ heta JA}$	40	°C/W

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
OFF CHARACTERISTICS				•	•	•
Collector-emitter breakdown voltage, gate-emitter short-circuited	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	BV <sub>CES</sub>	650	-	-	V
Temperature Coefficient of Breakdown Voltage	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	-	0.6	-	V/°C
Collector–emitter cut–off current, gate–emitter short–circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 650 V	I <sub>CES</sub>	-	-	250	μΑ
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	-	±400	nA
ON CHARACTERISTICS						
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$ , $I_C = 50 \text{ mA}$	$V_{GE(th)}$	3.4	4.9	6.4	V
Collector-emitter saturation voltage	$V_{GE}$ = 15 V, $I_{C}$ = 50 A $V_{GE}$ = 15 V, $I_{C}$ = 50 A, $T_{J}$ = 175°C	V <sub>CE(sat)</sub>	-	1.6 1.9	2.1 -	V
DYNAMIC CHARACTERISTICS						
Input capacitance	V <sub>CE</sub> = 30 V,	C <sub>ies</sub>	-	3098	-	pF
Output capacitance	V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	-	265	-	-
Reverse transfer capacitance		C <sub>res</sub>	-	9	-	
Gate charge total	V <sub>CE</sub> = 400 V,	$Q_g$	-	94	-	nC
Gate to emitter charge	I <sub>C</sub> = 50 V, V <sub>GE</sub> = 15 V	$Q_ge$	-	18	-	
Gate to collector charge		$Q_{gc}$	=	23	-	
SWITCHING CHARACTERISTICS						
Turn-on delay time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	-	17.6	-	ns
Rise time	VCC = 400 V, IC = 12.5 A	t <sub>r</sub>	_	6.4	-	
Turn-off delay time	$R_G = 4.7 \Omega$ $V_{GE} = 15 V$	t <sub>d(off)</sub>	_	94.4	-	
Fall time	Inductive Load	t <sub>f</sub>	_	14.4	-	
Turn-on switching loss		E <sub>on</sub>	=	131	-	μJ
Turn-off switching loss		E <sub>off</sub>	_	96	-	
Total switching loss		E <sub>ts</sub>	_	227	-	
Turn-on delay time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	_	19.2	-	ns
Rise time	VCC = 400 V, IC = 25 A	t <sub>r</sub>	_	11.2	-	
Turn-off delay time	$R_G = 4.7 \Omega$ $V_{GE} = 15 V$	td <sub>(off)</sub>	_	89.6	-	
Fall time	Inductive Load	t <sub>f</sub>	-	6.4	-	
Turn-on switching loss	1	Eon	-	311	-	μJ
Turn-off switching loss	1	Eoff	-	141	-	
Total switching loss	1	Ets	_	452	-	

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
SWITCHING CHARACTERISTICS				•		•
Turn-on delay time	T <sub>J</sub> = 175°C	t <sub>d(on)</sub>	=	16	-	ns
Rise time	VCC = 400 V, IC = 12.5 A	t <sub>r</sub>	=	8	-	
Turn-off delay time	$R_G = 4.7 \Omega$ $V_{GE} = 15 V$	t <sub>d(off)</sub>	=	107.2	-	
Fall time	Inductive Load	t <sub>f</sub>	=	53.6	-	
Turn-on switching loss		E <sub>on</sub>	-	157	-	μJ
Turn-off switching loss		E <sub>off</sub>	-	193	-	
Total switching loss		E <sub>ts</sub>	-	350	-	
Turn-on delay time	T <sub>J</sub> = 175°C	t <sub>d(on)</sub>	-	17.6	-	ns
Rise time	VCC = 400 V, IC = 25 A	t <sub>r</sub>	-	14.4	-	
Turn-off delay time	$R_G = 4.7 \Omega$ $V_{GE} = 15 V$	t <sub>d(off)</sub>	_	99.2	-	
Fall time	Inductive Load	t <sub>f</sub>	_	9.6	-	
Turn-on switching loss		E <sub>on</sub>	_	350	-	μJ
Turn-off switching loss		E <sub>off</sub>	_	328	-	
Total switching loss		E <sub>ts</sub>	_	678	-	
DIODE CHARACTERISTICS						
Forward voltage	I <sub>F</sub> = 20 A I <sub>F</sub> = 20 A, T <sub>J</sub> = 175°C	V <sub>F</sub>	-	1.45 1.83	1.75 -	٧
Total Capacitance	V <sub>R</sub> = 400 V, f = 1 MHz	С	_	103	-	pF
	V <sub>R</sub> = 600 V, f = 1 MHz	7	-	99	-	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**

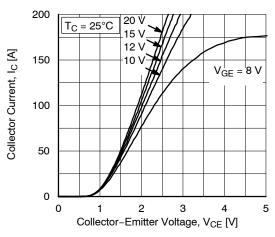


Figure 1. Typical Output Characteristics  $(T_C = 25^{\circ}C)$ 

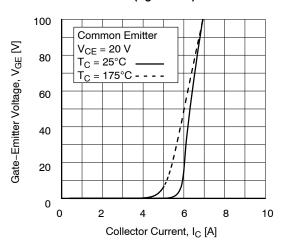


Figure 3. Transfer Characteristics

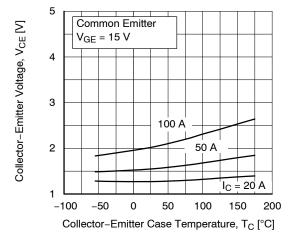


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

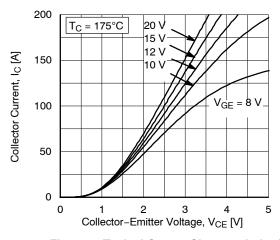


Figure 2. Typical Output Characteristics "
(T<sub>C</sub> = 175°C)

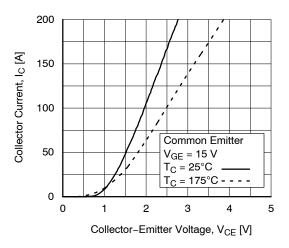


Figure 4. Typical Saturation Voltage Characteristics

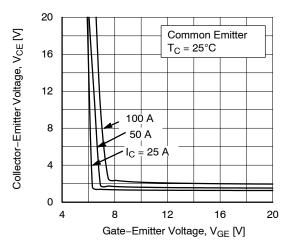


Figure 6. Saturation Voltage vs.  $V_{GE}$  ( $T_C = 25^{\circ}C$ )



#### TYPICAL CHARACTERISTICS (continued)

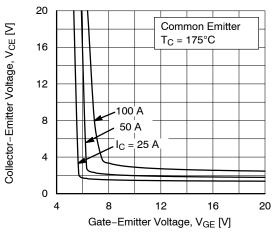


Figure 7. Saturation Voltage vs. V<sub>GE</sub> (T<sub>C</sub> = 175°C)

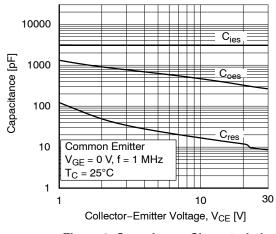


Figure 8. Capacitance Characteristics

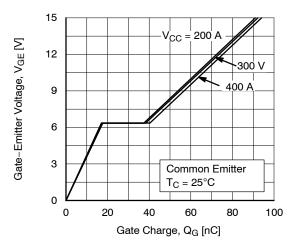


Figure 9. Gate Charge Characteristics ( $T_C = 25^{\circ}C$ )

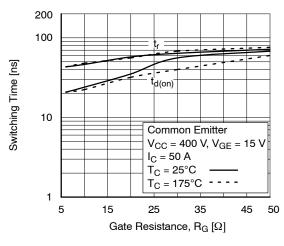


Figure 10. Turn-on Characteristics vs. Gate Resistance

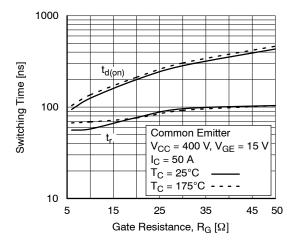


Figure 11. Turn-Off Characteristics vs. Resistance

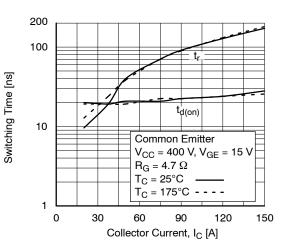


Figure 12. Turn-On Characteristics vs. Collector Current

#### TYPICAL CHARACTERISTICS (continued)

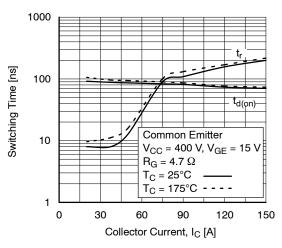


Figure 13. Turn-Off Characteristics vs. Collector Current

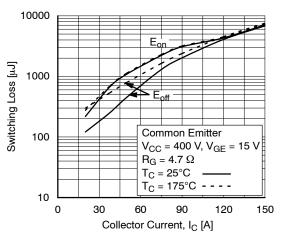


Figure 15. Switching Loss vs. Collector Current

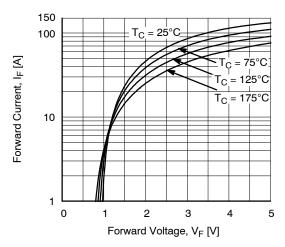


Figure 17. (Diode) Forward Characteristics vs. (Normal I–V)

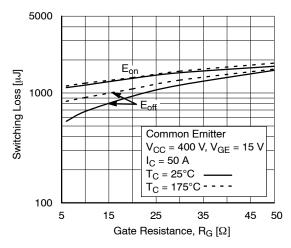


Figure 14. Switching Loss vs. Gate Resistance

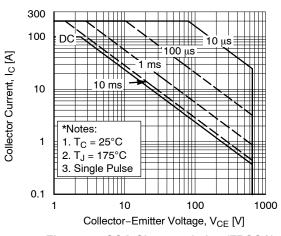


Figure 16. SOA Characteristics (FBSOA)

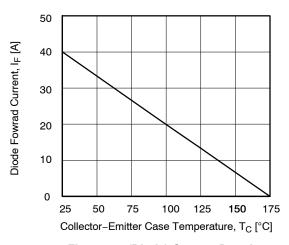


Figure 18. (Diode) Current Derating

### TYPICAL CHARACTERISTICS (continued)

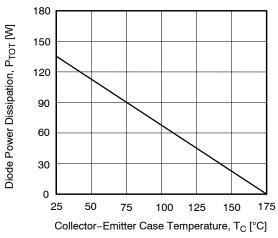


Figure 19. (Diode) Power Derating

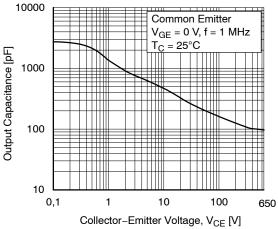


Figure 20. (Diode) Output Capacitance (Coes) vs. Reverse Voltage

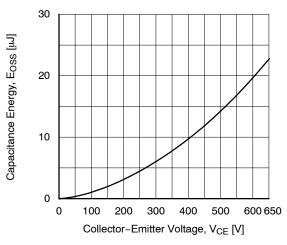


Figure 21. Output Capacitance Stored Energy

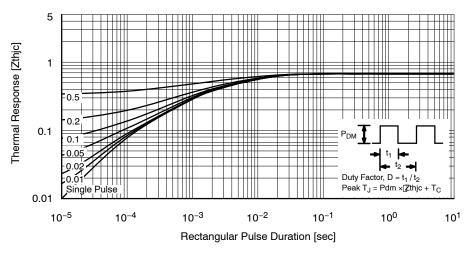


Figure 22. Transient Thermal Impedance of IGBT

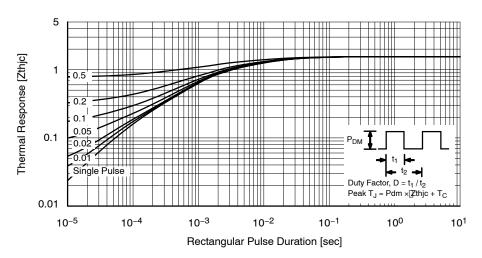
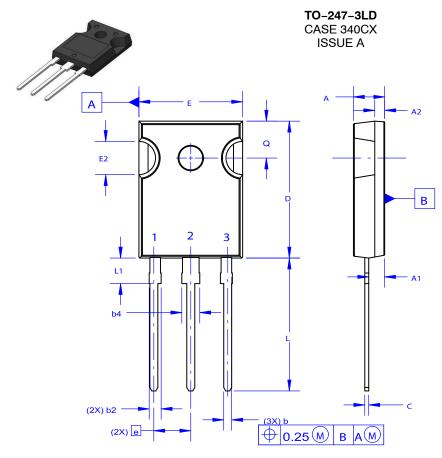


Figure 23. Transient Thermal Impedance of Diode

**DATE 06 JUL 2020** 





NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

# GENERIC MARKING DIAGRAM\*



XXXXX = Specific Device Code A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.

Ø <sub>P</sub> —		Φ <sub>P1</sub> D2
E1 —	2	D1
		I

DIM	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	4.58	4.70	4.82	
<b>A</b> 1	2.20	2.40	2.60	
A2	1.40	1.50	1.60	
D	20.32	20.57	20.82	
E	15.37	15.62	15.87	
E2	4.96	5.08	5.20	
е	~	5.56	~	
L	19.75	20.00	20.25	
L1	3.69	3.81	3.93	
ØΡ	3.51	3.58	3.65	
Q	5.34	5.46	5.58	
S	5.34	5.46	5.58	
b	1.17	1.26	1.35	
b2	1.53	1.65	1.77	
b4	2.42	2.54	2.66	
С	0.51	0.61	0.71	
D1	13.08	~	~	
D2	0.51	0.93	1.35	
E1	12.81	~	~	
ØP1	6.60	6.80	7.00	

DOCUMENT NUMBER:	98AON93302G	Electronic versions are uncontrolled except when accessed directly from the Document Repo Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	TO-247-3LD		PAGE 1 OF 1

onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems. or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$ 

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales